

Mutation analysis for systemC designs at TLM

Guarnieri, Valerio; Bombieri, Nicola; Pravadelli, Graziano; Fummi, Franco; **Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes** 12th IEEE Latin American Test Workshop (LATW) : Porto de Galinhas, Brasil, 27-30 March 2011 2011 / [6] p
<https://ieeexplore.ieee.org/document/5985925>

Mutation analysis with high-level decision diagrams

Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Tšepurov, Anton; Ubar, Raimund-Johannes; Guglielmo, Giuseppe di; Fummi, Franco LATW2010 : 11th Latin-American TestWorkshop, March 28-31, 2010, Punta del Este, Uruguay 2010 / [6] p. [CD-ROM] <https://ieeexplore.ieee.org/document/5550336>

On the combined use of HLDDs and EFSMs for functional ATPG

Di Guglielmo, Giuseppe; Fummi, Franco; **Jenihhin, Maksim**; Pravadelli, Graziano; **Raik, Jaan; Ubar, Raimund-Johannes** 5th IEEE East-West Design & Test Symposium EWDTS 2007 : September 7-10, 2007, Yerevan, Armenia 2007 / p. 503-508 : ill